micro resist technology GmbH Köpenicker Straße 325 12555 Berlin Germany

Tel.: +49 (0) 30 641670100

Fax: +49 (0) 30 641670200

info@microresist.de

www.microresist.com

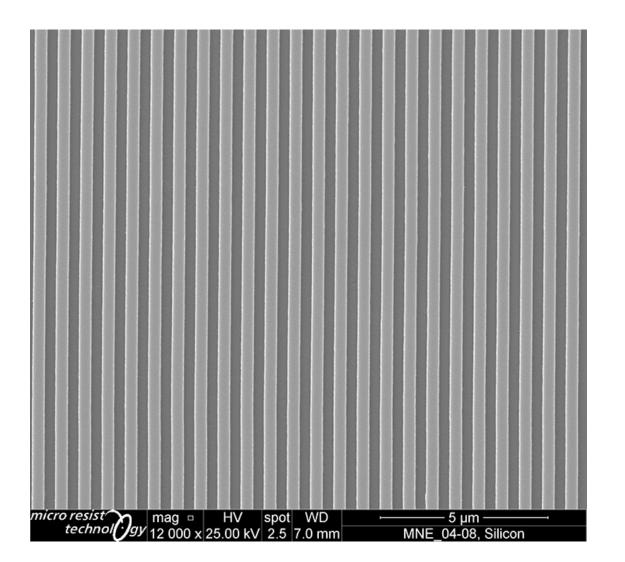


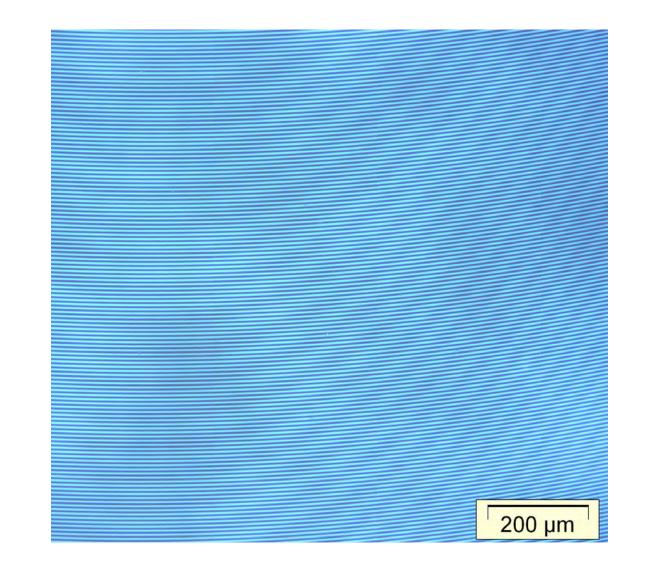
# mr-NIL200 Series – Next Generation UV-NIL Resist for Industrial Manufacturing of Micro and Nanopatterns

The mr-NIL200 series are photo-curable NIL resist formulations specifically developed for UV nanoimprint lithography (UV-NIL) applying gas-impermeable stamp materials. The typical application field of mr-NIL200 is the use as an etch mask in pattern transfer processes for e.g. photonic applications via reactive ion etching approaches. The mr-NIL200 series is available as ready-to-use formulations and works without the need for any additional adhesion promoter or primer.

## **Application examples**

High accuracy UV-NIL using mr-NIL200 for e.g. photonic applications

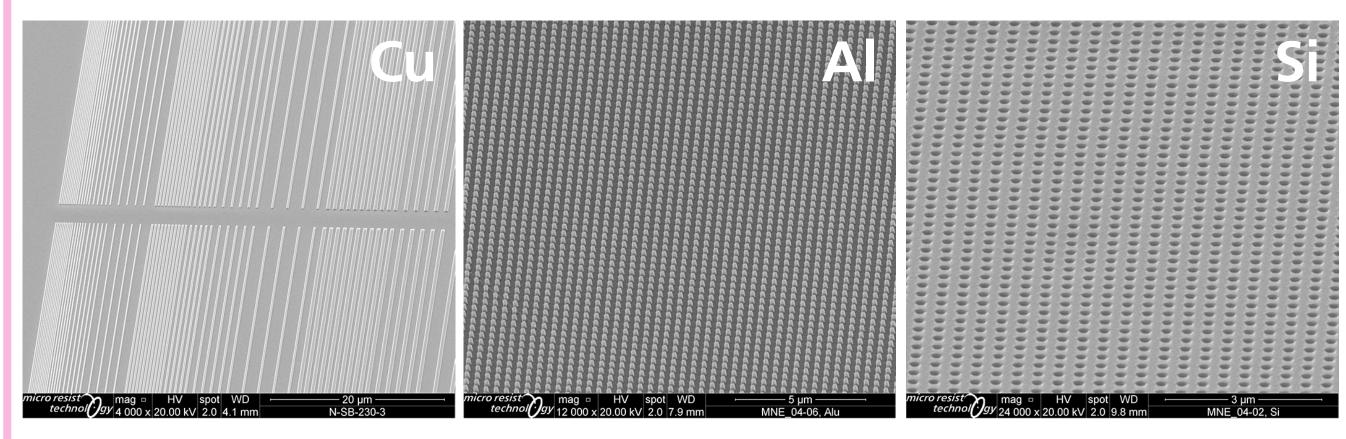




mr-NIL200-200nm imprints of photonic zone plate structures on Si (360nm width, 700nm pitch, 150nm depth)

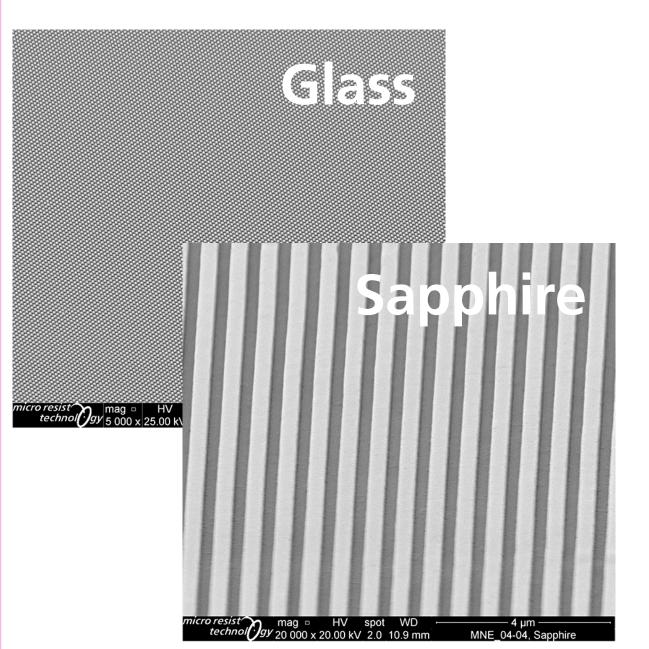
Primer-free imprinting for high volume manufacturing: No adhesion promoter needed for various substrates

#### Silicon wafers and metal substrates

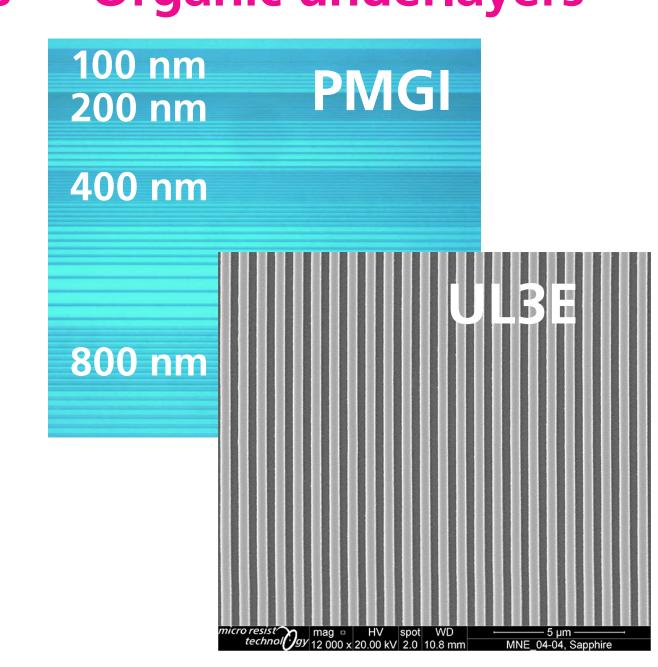


mr-NIL200-200nm imprints of L&S pattern on Cu, 25x25 mm<sup>2</sup> dense pillar array on Al ( $\emptyset$  = 200nm, height = 300 nm), and the inverted array on glass.

## Oxidic substrate materials Organic underlayers



mr-NIL200-200nm imprints of photonic color pattern on sapphire (360nm width, 700nm pitch, AR1and 25x25 mm<sup>2</sup> dense pillar array on glass (right,  $\emptyset$  = 200nm, height = 300 nm)



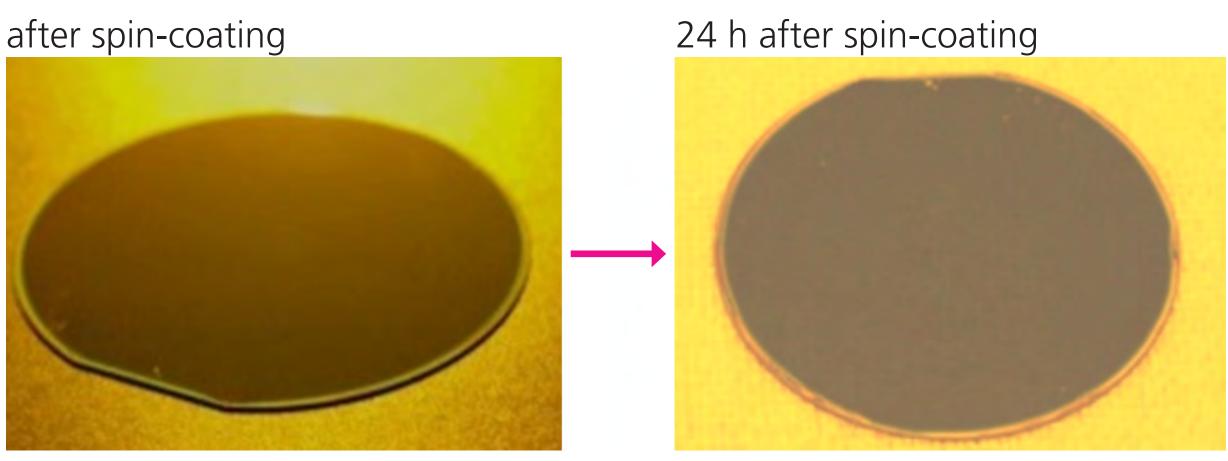
mr-NIL200-200nm imprints of L&S arrays on Polymethylglutarimid PMGI/LOR (depth 100nm) for alkaline lift-off and 350nm L&S pattern AR1 on UL3E underlayer for neutral lift-off

## Main product features

- Primer-free coating ("self-priming") of substrates like Si, metals (e.g. Cu or Al), oxidic materials (e.g.  $SiO_2$  or  $Al_2O_3$ ), and underlayer materials (e.g. LOR, UL1, or UL3E)
- UV-curing chemistry insensitive towards ambient atmosphere and oxygen
- Low viscosity renders fast cavitity filling of small structures by capillary forces
- Etch mask for nanopattern transfer via e.g. RIE

#### Film characteristics

- Outstanding film stability and film thickness uniformity over several hours without the need of additional primers.
- Example: 100nm thin film on oxygen plasma cleaned Si wafers persist for several hours:



Available film thickness: 100 nm, 200 nm, 300 nm and other film thickness available on request

#### **Photo-Nanoimprinting**

- Fast filling of small cavities due to low resist viscosity (200 mPas after spin-coating and pre-bake)
- Particularly suitable for being applied in combination with gasimpermeable working stamp materials (e.g. OrmoStamp®, COC, FEP)
- Features additional fluorinated additive to lower stamp release forces
- Photo-curing by LED (up to 405 nm) or H<sub>a</sub> bulb exposure

## Dry etching characteristics and stripping

- Excellent etching characteristics for many demanding substrates like sapphire, silica, etc.
- Residue-free removal of cured resist by oxygen plasma stripping